

ABSTRACT OF THE DISCLOSURE

When used as a test data generator, CDR internal structures may be applied to generate drift conditions in the test data. For example, a finite state machine phase shifts a clock signal, over time, driving the test data generator thereby producing a drift condition on the test data. Once the test is completed, one of the other CDRs may be used as a tester to similarly generate test data for the first CDR. CDRs may be configured in pairs for this purpose so that one may be used to test the other.